A STATISTICAL ANALYSIS OF SOME ESTIMATORS OF RELIABILITY

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NAVAL POSTGRADUATE SCHOOL

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THESIS

A STATISTICAL ANALYSIS
OF
SOME ESTIMATORS OF RELIABILITY

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A Statistical Analysis of Some Estimators of Reliability

by

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ABSTRACT

This thesis presents a computer assisted, comparative analysis of empirical, maximum likelihood and exponential procedures for estimating reliability. The deviations of the estimators from the true reliability, when the underlying failure rate is monotone, are compared using the Kolmogorov-Smirnov family of statistics. The behavior of the distributions of these deviations, for various sample sizes and failure rates is examined. Finally, the considerations of when to use which estimator are discussed.



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I. INTRODUCTION

Assumptions concerning the form of the underlying failure distribution are made in most analyses of reliability problems. When these assumptions are in error the conclusions reached may be grossly in error.

Some alternatives to making assumptions about the form of the underlying failure distribution are maximum likelihood estimation and empirical estimation.

This work presents a comparative analysis of empirical, maximum likelihood, and the often used exponential procedures when the underlying failure distribution has a monotone non-decreasing failure rate. The maximum likelihood estimator is formed under the assumption that the underlying failure rate is monotone non-decreasing. The hypothesis that a sample of failure times comes from a distribution having a monotone failure rate can be tested using the method contained in Ref. 1.

The relative quality of the three estimators was examined using the Kolmogorov-Smirnov family of statistics.

The following notation and definitions are used in the succeeding sections. Let F be a right continuous distribution such that F (0^-) = 0. If F has a density f then $r(t) = \frac{f(t)}{R(t)}$ is the failure rate, where $R(t) = 1 - F(t) \text{ is the reliability or the survival probability.} \quad \text{Thus}$ $R(t) = \exp\left[-\int_{-\infty}^t r(z) \mathrm{d}z\right] \quad \text{A distribution has an increasing failure rate}$



(IFR) if r(t) is monotone non-decreasing in t, and has a decreasing failure rate (DFR) if r(t) is monotone non-increasing in t.



II. THE ESTIMATORS

A. THE EMPIRICAL ESTIMATOR

The empirical estimator of reliability, Remp(t), based on a sample of n ordered observations $(t_1 \le t_2 \le \ldots \le t_n)$ from a failure distribution F is;

$$Remp(t) = 1.0 t < t_1$$

$$Remp(t) = (n-i)/n \qquad t_i \le t < t_{i+1}$$

$$Remp(t) = 0 t \ge t_n$$

B. THE EXPONENTIAL ESTIMATOR

The exponential estimator of reliability based on the above sample is $Rexp(t) = exp\left[-kt\right]$, $t \ge 0$, where 1/k is the maximum likelihood estimate of the mean of the exponential distribution and is equal to the sample mean.

C. THE MAXIMUM LIKELIHOOD ESTIMATOR

The derivation of the maximum likelihood estimator is dependent upon an assumption that the underlying distribution has IFR or DFR.

The IFR case is outlined here. Both the IFR and DFR cases are presented in detail in Ref. 1.

Let $t_1 \le t_2 \le \ldots \le t_n$ be a sample of n ordered observations from F, IFR. Using the fact that



 $R(t) = \exp\left[-\int_{-\infty}^t r(z) dz\right] \quad \text{and} \ r(t) = \frac{f(t)}{R(t)} \ \text{the log likelihood may be}$ expressed as

$$L = \log(n!) + \sum_{i=1}^{n} \log f(t_i) = \sum_{i=1}^{n} \log r(t_i) - \sum_{i=1}^{n} \int_{-\infty}^{t_i} r(z) dz + \log(n!).$$

The maximization of L, subject to r(t) monotone non-decreasing, yields as an estimator for r(t)

$$\hat{r}(t) = \min_{v \ge i+1} \max_{u \le i} \left[v - u \right] \left[(n-u)(t_{u+1} - t_u + \dots + (n-v+1)(t_v - t_{v-1}) \right]^{-1}$$

$$\begin{split} &i=1,2,\dots,n\text{--}1 \text{ and } \widehat{r}(t_n)\text{=}\infty\text{ . For the remaining values of } t,\widehat{r}(t) \text{ is } 0\\ &\text{for } 0\leq t < t_1 \text{ ,}\infty \text{ for } t > t_n \text{, and constant (right continuous) between}\\ &\text{observations. The corresponding estimator, } \widehat{R}(t)\text{, is obtained from}\\ &\widehat{R}(t)=\exp\left[-\int_{-\infty}^t \widehat{r}(z)\mathrm{d}z\right]\text{ . Reference 1 shows that } \widehat{r}(t)\text{ is a consistent}\\ &\text{estimator of } r(t)\text{.} \end{split}$$



III. PROCEDURES

To evaluate the estimators of R(t), computer simulation (Fortran IV, IBM-360, W. R. Church Computer Center, Naval Postgraduate School) was used to generate samples of failure times, compute the estimators and the statistics used in their evaluation.

Two parent distributions were used, the Weibull and the Erlang. The Weibull distribution has reliability function $R(t) = e^{-bt^a}$ with shape parameter a>0 and scale parameter b>0. The failure rate of the Weibull distribution is $r(t)=abt^{a-1}$. When a=1 the distribution is the exponential. For values of $a\ge 1$ the Weibull distribution has IFR.

The Erlang distribution was used to investigate whether the results were dependent upon the parent distribution used. The Erlang distribution has reliability function $R(t) = \int_{t}^{\infty} \frac{x^{a-1} b^a e^{-bx}}{(a-1)!} dx$ where a>0, b>0 and a is an integer. The failure rate of the Erlang distribution is $r(t) = \frac{t^{a-1} b^a e^{-bt}}{R(t)}$. When a=1 the distribution is the exponential. When $a \ge 1$ the Erlang distribution has IFR and the failure rate is bounded above by b.

Consider a sample of n independent, identically distributed realizations of Weibull failure times. The true reliability of a system with this underlying distribution is $R(t) = e^{-bt^a}$. Let Remp(t) be the empirical estimator of R(t) as computed from this sample and let $Demp = \sup_{t} \left| Remp(t) - R(t) \right| .$ Then Demp is a one-sample, two-sided,



Kolmogorov-Smirnov statistic. Computing Demp for each of one hundred independent samples and ordering the results yields an empirical distribution of the statistic Demp.

Repeating this procedure for each estimator gives empirical distributions for the statistics $\text{Dexp} = \sup_t \left| \text{Rexp}(t) - \text{R}(t) \right|$ and $\text{Dmle} = \sup_t \left| \text{Rmle}(t) - \text{R}(t) \right|$. Let Fdemp(x) be the empirical distribution function of the statistic Demp. Similarly, let Fdexp(x) and Fdmle(x) be the empirical distribution functions of Dexp and Dmle respectively.

For a given set of Weibull distribution parameters and a given sample size, define;

$$D_{1}^{+} = \sup_{x} \left[\text{Fdemp(x)} - \text{Fdmle(x)} \right]$$

$$D_{1}^{-} = \sup_{x} \left[\text{Fdmle(x)} - \text{Fdemp(x)} \right]$$

$$D_{2}^{+} = \sup_{x} \left[\text{Fdmle(x)} - \text{Fdexp(x)} \right]$$

$$D_{2}^{-} = \sup_{x} \left[\text{Fdexp(x)} - \text{Fdmle(x)} \right]$$

$$D_{3}^{+} = \sup_{x} \left[\text{Fdemp(x)} - \text{Fdexp(x)} \right]$$

$$D_{3}^{-} = \sup_{x} \left[\text{Fdexp(x)} - \text{Fdemp(x)} \right]$$

These statistics are two-sample, one-sided, Kolmogorov-Smirnov statistics and can be used to test the following types of hypotheses; Ho: Fdemp(x) = Fdexp(x) against the alternative H1: $Fdemp(x) \ge Fdexp(x)$.

To define the critical region for this test, note that $P\left[D_3^+ \leq D^+(\alpha)\right] = 1-\alpha \text{, where } D^+(\alpha) \text{ is the } 1-\alpha \text{ percentile of the two-sample, one-sided, Kolmogorov-Smirnov statistic distribution.}$



Reference 2 gives an approximation to the limiting distribution of D⁺as

$$\lim_{\substack{n_1 \to \infty \\ n_2 \to \infty}} \mathbb{P} \left[\mathbf{D}^+ < \mathbf{x} \, \sqrt{\frac{\mathbf{n}_1 + \mathbf{n}_2}{\mathbf{n}_1 \mathbf{n}_2}} \right] = 1 - \mathbf{x} = 1 - \mathbf{e}^{-2\mathbf{x}^2} \quad \text{where } \mathbf{n}_1 \text{ and } \mathbf{n}_2 \text{ are } \mathbf{n}_2 \to \mathbf{x}$$

the sample sizes of the two distributions tested.

For a test of the hypothesis Ho: Fdemp(x) = Fdexp(x) against the alternative H1: Fdemp(x) \neq Fdexp(x), the two-sample, two-sided Kolmogorov-Smirnov test may be used. The statistic is D_3 =max $\left[D_3^+, D_3^-\right]$. Reference 3 defines the limiting distribution of D and Ref. 2 gives the following approximation

$$\lim_{\substack{n_1 \to \infty \\ n_2 \to \infty}} P \left[D < x \sqrt{\frac{n_1 + n_2}{n_1 n_2}} \right] = 1 - \alpha \doteq 1 - 2e^{-2x^2}$$

for values of x sufficiently large.



IV. RESULTS

The failure rates examined vary from r(t) = 1.0, the case when the underlying distribution is exponential, to $r(t) = 2.139t^2$. In each case the mean time to failure is equal to one.

The important difference in these failure rates is their relative rate of change with t. Throughout the remainder of this discussion the term high failure rate refers to a failure rate with a relatively high rate of change with t. Thus $r(t) = t^2$ is a higher failure rate than r(t) = t.

Table I contains the statistics D_1^+ and D_1^- , as defined in Section III. The critical values of these statistics, at a level of significance of .01, are $D_{\rm crit}^+(.01)=D_{\rm crit}^-(.01)=0.215$. At a level of significance of .05 $D_{\rm crit}^+(.05)=D_{\rm crit}^-(.05)=0.173$. The statistic D can be determined from the table by using the fact that $D=\max\left[D^+,D^-\right]$. The critical values of D at levels of significance of .01 and .05 are $D_{\rm crit}^-(.01)=0.230$ and $D_{\rm crit}^-(.05)=0.192$.

At a level of significance of .01 the hypothesis Ho: Fdmle(x) = Fdemp(x) is rejected in favor of H1: Fdemp(x) \neq Fdmle(x) when $D_1 > 0.230$. Ho is rejected in favor of H1: Fdemp(x) \geq Fdmle(x) when $D_1^+ > 0.215$.

Reversing the sense of the inequality in H1 and replacing D_1^+ by D_1^- , the test becomes, reject H0 in favor of H1: Fdmle(x) \geq Fdemp(x) when $D_1^- > 0.215$.



As all samples of Dexp, Demp and Dmle are of the same size and the Kolmogorov-Smirnov statistics are independent of the distributions being tested, these critical values of D^+ and D^- can be used for all cases presented here.

TABLE I

Observed values of $D_1^+ = \sup_{x} \left[\text{Fdemp}(x) - \text{Fdmle}(x) \right]$ and $D_1^- = \sup_{x} \left[\text{Fdmle}(x) - \text{Fdemp}(x) \right]$ for sample size n and failure rate r(t)

r (t)	n=10		n= 15		n = 20		n=25		n=30	
1 (1)	Dţ	D ₁	D ₁ ⁺	D ₁	D_1^+	D ₁	D_1^+	D ₁	D_1^+	D_1^-
1.0	0.57	0	0.73	0	0.79	0	0.96	0	0.98	0
1.287 t ^{.5}	0.47	0	0.66	0	0.76	0	0.91	0	0.97	0
4t 2t - 1	0.43	0	0.70	0	0.85	0	0.92	0	0.97	0
1.571t	0.47	0	0:66	0	0.74	0	0.91	0	0.97	0
1.794t ^{1.5}	0.47	0	0.65	0	0.74	0	0.91	0	0.97	0
2.139 t ²	0.46	0	0.65	0	0.74	0	0.91	0	0.97	0

In all cases presented in Table I the value of D_1^- is zero and the value of D_1^+ is significantly large which implies that the empirical estimator deviates less from the true reliability than does the maximum likelihood estimator.

As the sample size increases, it is expected that the deviations of both estimators will decrease. The data in Table I indicate that the deviations of Remp(t) are decreasing faster than the deviations of Rmle(t).



Before examining some of the sample points of the distributions Fdemp(x) and Fdmle(x), it should be noted that the sample 100^{th} percentile of Fdmle, denoted by Dmle(100), is the maximum deviation of Dmle for all samples of fixed size n with the same underlying failure rate. Similarly, Dmle(1) is the minimum deviation and Dmle(100) - Dmle(1) is the sample range of Dmle.

As Demp is a one-sample, two-sided Kolmogorov-Smirnov statistic, it is independent of the distributions tested and will vary only with sample size. This is not true of Dexp and Dmle.

When the failure rate is 2.139t² and the sample size increases from 10 to 30, Demp(100) decreases from .4120 to .2690, a reduction of about 35% in maximum deviation. Over the same range of sample sizes Dmle(100) decreases from .5426 to .4470, a reduction of about 15% in the maximum deviation. For the same changes in sample size, Dmle(1) varies from .1816 to .1810 while Demp(1) varies from .1210 to .0671. This implies that the entire range of Demp moves toward the origin as the sample size increases, while only the right hand tail of Dmle moves with changes in sample size. When the failure rate is constant the variation in Dmle(100) is from .6956 to .6165 while the variation in Dmle(1) is from .1974 to .1899.

The data in Table II indicate that the deviations of the exponential estimator are stochastically smaller than the deviations of the maximum likelihood estimator for all failure rates tested.



TABLE II

Observed values of $D_2^+ = \sup_{x} \left[Fdmle(x) - Fdexp(x) \right]$ and $D_2^- = \sup_{x} \left[Fdexp(x) - Fdmle(x) \right]$ for sample size n and failure rate r(t)

(1)	n = 10		n = 15		n = 20		n = 25		n = 30	
r (t)	D ₂ ⁺	D ₂								
1.0	0	0.88	0	0.94	0	0.93	0	0.99	0	0.99
1.287 t ⁻⁵	0	0.84	0	0.82	0	0.88	0	0.95	0	0.98
4t 2t-1	0	0.83	0	0.92	0	0.93	0	0.95	0	0.98
1.571t	0	0.63	0	0.64	0	0.78	0	0.82	0	0.93
1.794 t ^{1.5}	0.03	0.47	0.08	0.47	0.05	0.57	0.02	0.76	0.01	0.81
2.139 t ²	0.13	0.30	0.12	0.31	0.09	0.37	0.01	0.51	0.04	0.64

For a given failure rate, the magnitude of D_2^- increases with sample size and for a fixed sample size it decreases as the failure rate increases.

The behavior of the distributions of Dexp and Dmle are best illustrated graphically. Figures 1 through 4 depict a smoothed form of the empirical distributions as sample size and failure rate vary.



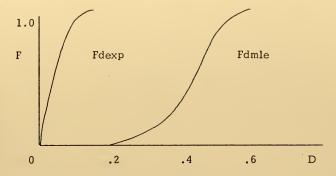


Fig. 1. Fdexp and Fdmle for n = 30 and r(t) = 1.0

Note: Dexp(1) = 0.0001 Dexp(100) = 0.1651

Dmle (1) = 0.1899 Dmle (100) = 0.6165

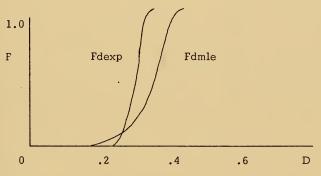


Fig. 2. Fdexp and Fdmle for n = 30 and $r(t) = 2.139t^2$

Note: Dexp (1) = 0.2610 Dexp (100) = 0.3565

Dmle (1) = 0.1814 Dmle (100) = 0.4473



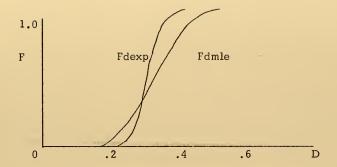


Fig. 3. Fdexp and Fdmle for n = 10 and $r(t) = 2.139t^2$ Note: Dexp(1) = 0.2399 Dexp(100) = 0.4291 Dmle(1) = 0.1816 Dmle(100) = 0.5462

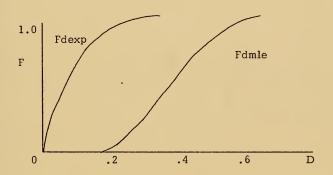


Fig. 4. Fdexp and Fdmle for n = 10 and r(t) = 1.0Note: Dexp(1) = 0.0010 Dexp(100) = 0.3571

Dmle(1) = 0.1979 Dmle(100) = 0.6456



As would be expected, the exponential estimator performs best when the failure rate is low and the sample size is large. As the failure rate increases Fdexp moves to the right and the range of Dexp decreases.

The range of Dmle decreases as sample size increases or as failure rate increases. The first percentile of the distribution is relatively insensitive to change in either sample size or failure rate.

For all cases, Ho: Fdmle(x) = Fdexp(x) can be rejected in favor of H1: $Fdexp(x) \ge Fdmle(x)$ at level .01.

The data in Table III indicate that the exponential estimator deviates less from the true reliability than does the empirical estimator when the failure rate is constant or nearly constant. When the failure rate is constant, $D_3^+=0$ and D_3^- increases with the sample size, n. This is consistent with the theory as the maximum likelihood estimate of the parameter of the exponential distribution is the reciprocal of the sample mean and $\lim_{n\to\infty} \bar{x} = \mu$.



TABLE III

Observed values of
$$D_3^+ = \sup_{x} \left[\text{Fdemp}(x) - \text{Fdexp}(x) \right]$$
 and $D_3^- = \sup_{x} \left[\text{Fdexp}(x) - \text{Fdemp}(x) \right]$ for sample size n and failure rater(t)

r(t)	n = 10		n = 15		n = 20		n = 25		n = 30	
1(1)	D ₃ ⁺	D ₃								
1.0	0	0.72	0	0.74	0	0.76	0	0.80	0	0.78
1.287 t·5	0	0.60	0	0.43	0.05	0.29	0.01	0.23	0.08	0.25
4t 2t-1	0	0.63	0.02	0.43	0.02	0.20	0.06	0.26	0.13	0.15
1.571t	0.08	0.24	0.30	0.03	0.43	0.06	0.55	0.01	0.66	0
1.794 t ^{1.5}	0.30	0.03	0.63	0	0.66	0.01	0.88	0	0.92	0
2.139 t ²	0.52	0	0.82	0	0.83	0	0.95	0	0.98	0

As the failure rate becomes larger, D_3^- decreases to zero. D_3^+ increases with both sample size and failure rate. When the failure rate is not constant, D_3^- decreases with sample size.

Figures 5 through 8 show the behavior of Fdemp and Fdexp with changes in failure rate and sample size.



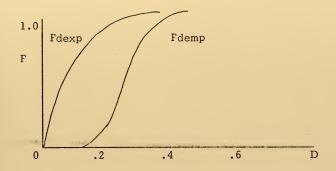


Fig. 5. Fdexp and Fdemp for n = 1.0 and r(t) = 1.0

Note: Dexp(1) = 0.001

Dexp(100) = 0.3571

Demp(1) = 0.1207

Demp (100)= 0.4122

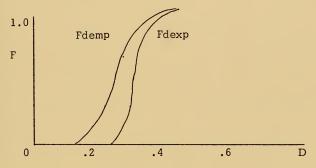


Fig. 6. Fdexp and Fdemp for n = 10 and $r(t) = 2.139 t^2$

Note: I

Dexp(1) = 0.2399

Dexp(100) = 0.4291

Demp(1) = 0.1207

Demp(100) = 0.4122



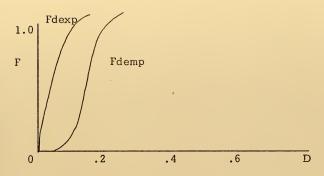


Fig. 7. Fdexp and Fdemp for n = 30 and r(t) = 1.0

Note: Dexp(1) = 0.0001 Dexp(100) = 0.1651

Demp (1)= 0.0670 Demp (100) = 0.2690

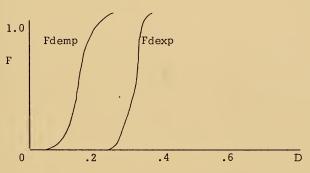


Fig. 8. Fdexp and Fdemp for n = 30 and $r(t) = 2.139 t^2$

Note: Dexp (1) = 0.2610 Dexp (100) = 0.3565 Demp (1) = 0.0670 Demp (100) = 0.2690

Note that the distribution Fdemp is invariant with changes in failure rate and varies only with the sample size. The changes in D_3^+ and D_3^- for a given sample size occur because the distribution Fdexp varies with r(t). As r(t) increases Fdexp moves to the right



for all sample sizes examined. For high failure rates the left end.

point of Fdexp moves away from the origin as sample size increases

while the right end point moves toward the origin.

The stochastic ordering of Fdexp and Fdemp varies with the underlying failure rate with Fdemp \geq Fdexp for higher failure rates.



V. CONCLUSIONS

The statistics in Tables I and II support the hypothesis that the empirical and the exponential estimators give better estimates of reliability than does the maximum likelihood estimator for the cases considered.

Comparing the exponential and the empirical estimators, it can be seen that while both sample size and failure rate affect the magnitudes of D^+ and D^- , the failure rate of the underlying distribution is the factor that determines the stochastic ordering of the distributions Fdemp and Fdexp.

The exponential estimator would be the logical choice when the underlying failure rate is constant, or nearly constant, while the empirical estimator performs better when the failure rate is higher.

In considering the question of when to use which estimator it is necessary to investigate the nature of the underlying failure rate.

Reference 4 contains several tests for the validity of the assumption that the underlying life distribution is exponential.

If physical considerations or tests, such as those presented in Ref. 4 substantiate the assumptions that the underlying distribution is exponential, then the exponential estimator of reliability should be used. If the exponential assumption cannot be substantiated, the empirical estimator should give better estimates of the system reliability than the exponential estimator.



Physical considerations of some systems indicate that the failure rate is not monotone but conforms to the bathtub model where the failure rate is initially high but decreasing, relatively constant for the middle age life periods, and increasing with old age. Some electronic components are believed to behave in this manner, experiencing a "burn-in" period at the onset of their working life cycle.

The empirical estimator should be particularly useful in cases where the failure rate is not monotone as no assumptions about the form of the underlying distribution, or its failure rate are required.



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This thesis presents a computer assisted, comparative analysis of empirical, maximum likelihood and exponential procedures for estimating reliability. The deviations of the estimators from the true reliability, when the underlying failure rate is monotone, are compared using the Kolmogorov-Smirnov family of statistics. The behavior of the distributions of these deviations, for various sample sizes and failure rates is examined. Finally, the considerations of when to use which estimator are discussed.



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A statistical analysis of some estimator

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